

Nano4me.org Video Download

E SC 216: Characterization, Testing of Nanotechnology Structures, and Materials

Unit 4: Advanced Scanning Probe Microscopy



Lecture 2

Length: 35:41

This video will cover:

- Atomic Force Microscopy
- Common Modes of Operation
- Pitfalls and Image Artifacts
- Example of Instrument Operation

Thank You For Watching!

What did you think? [Email](#) Bob Ehrmann with your feedback.

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